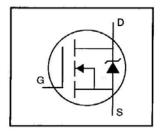


### HEXFET® Power MOSFET

- Ultra Low Gate Charge
- Reduced Gate Drive Requirement
- Enhanced 30V Vgs Rating
- Isolated Package
- High Voltage Isolation= 2.5KVRMS ⑤
- Sink to Lead Creepage Dist.= 4.8mm
- Repetitive Avalanche Rated
- Lead-Free

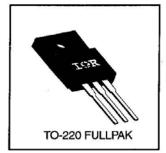
#### Description



 $V_{DSS} = 400V$   $R_{DS(on)} = 0.55\Omega$   $I_D = 5.7A$ 

This new series of Low Charge HEXFETs achieve significantly lower gate charge over conventional MOSFETs. Utilizing advanced HEXFET technology, the device improvements allow for reduced gate drive requirements, faster switching speeds and increased total system savings. These device improvements combined with the proven ruggedness and reliability that are characteristic of HEXFETs offer the designer a new standard in power transistors for switching applications.

The TO-220 Fullpak eliminates the need for additional insulating hardware. The moulding compound used provides a high isolation capability and low thermal resistance between the tab and external heatsink.



### **Absolute Maximum Ratings**

	Parameter	Max.	Units	
I <sub>D</sub> @ T <sub>C</sub> = 25°C	Continuous Drain Current, V <sub>GS</sub> @ 10 V	5.7		
I <sub>D</sub> @ T <sub>C</sub> = 100°C	Continuous Drain Current, V <sub>GS</sub> @ 10 V	3.6	A	
IDM	Pulsed Drain Current ①	23 .		
P <sub>D</sub> @ T <sub>C</sub> = 25°C	Power Dissipation	40	W	
	Linear Derating Factor	0.32	W/°C	
V <sub>GS</sub>	Gate-to-Source Voltage	±30	V	
Eas	Single Pulse Avalanche Energy ②	310	mJ	
IAR	Avalanche Current ①	5.7	Α	
EAR	Repetitive Avalanche Energy ①	4.0	mJ	
dv/dt	Peak Diode Recovery dv/dt ③	4.0	V/ns	
T <sub>J</sub> T <sub>STG</sub>	Operating Junction and Storage Temperature Range	-55 to +150	°C	
	Soldering Temperature, for 10 seconds	300 (1.6mm from case)		
	Mounting Torque, 6-32 or M3 screw	10 lbf•in (1.1 N•m)		

### **Thermal Resistance**

Document Number: 91155

	Parameter	Min.	Тур.	Max.	Units
Reuc	Junction-to-Case	_	_	3.1	°C/W
ReJA	Junction-to-Ambient	-		65	C/VV

Electrical Characteristics @ T.I = 25°C (unless otherwise specified)

	Parameter	Min.	Тур.	Max.	Units	Test Conditions
V <sub>(BR)DSS</sub>	Drain-to-Source Breakdown Voltage	400	-	_	٧	V <sub>GS</sub> =0V, I <sub>D</sub> = 250μA
ΔV <sub>(BR)DSS</sub> /ΔT <sub>J</sub>	Breakdown Voltage Temp. Coefficient	_	0.76	_	V/°C	Reference to 25°C, ID= 1mA
R <sub>DS(on)</sub>	Static Drain-to-Source On-Resistance	_	-	0.55	Ω	V <sub>GS</sub> =10V, I <sub>D</sub> =3.4A ④
V <sub>GS(th)</sub>	Gate Threshold Voltage	2.0	_	4.0	٧	V <sub>DS</sub> =V <sub>GS</sub> , I <sub>D</sub> = 250μA
gfs .	Forward Transconductance	3.0	-	-	S	V <sub>DS</sub> =50V, I <sub>D</sub> =6.0A ④
		-	_	25		V <sub>DS</sub> =400V, V <sub>GS</sub> =0V
loss	Drain-to-Source Leakage Current		-	250	μΑ	V <sub>DS</sub> =320V, V <sub>GS</sub> =0V, T <sub>J</sub> =125°C
	Gate-to-Source Forward Leakage	·	1-1	100	nA	V <sub>GS</sub> =20V
lgss	Gate-to-Source Reverse Leakage		1-	-100	l IIA	V <sub>GS</sub> ≃-20V
Qg	Total Gate Charge	1	_	39		I <sub>D</sub> =10A
Qgs	Gate-to-Source Charge		_	10	nC	V <sub>DS</sub> =320V
Q <sub>gd</sub>	Gate-to-Drain ("Miller") Charge	1-0	_	19		V <sub>GS</sub> =10V See Fig. 6 and 13 @
t <sub>d(on)</sub>	Turn-On Delay Time		11	-		V <sub>DD</sub> =200V
tr	Rise Time	-	31	_	ns	I <sub>D</sub> =10A
t <sub>d(off)</sub>	Turn-Off Delay Time	1	25	_	""	R <sub>G</sub> =9.1Ω
tf	Fall Time		20	-		R <sub>D</sub> =20Ω See Figure 10 ④
L <sub>D</sub>	Internal Drain Inductance	_	4.5	-	nН	Between lead, 6 mm (0.25in.) from package
Ls	Internal Source Inductance	-	7.5	-	,,,,	and center of die contact
Ciss	Input Capacitance		1100	-		V <sub>GS</sub> =0V
Coss	Output Capacitance		190	_	pF	V <sub>DS</sub> = 25V
Crss	Reverse Transfer Capacitance	-	18	_		f=1.0MHz See Figure 5
С	Drain to Sink Capacitance	_	12	1	pF	f=1.0MHz

#### Source-Drain Ratings and Characteristics

	Parameter	Min.	Тур.	Max.	Units	Test Conditions	
ls	Continuous Source Current (Body Diode)		_	5.7	A	MOSFET symbol showing the	
Ism	Pulsed Source Current (Body Diode) ①	_	_	23		integral reverse p-n junction diode.	
V <sub>SD</sub>	Diode Forward Voltage		_	2.0	V	TJ=25°C, IS=5.7A, VGS=0V 4	
t <sub>rr</sub>	Reverse Recovery Time		380	570	ns	T <sub>J</sub> =25°C, I <sub>F</sub> =10A	
Qrr	Reverse Recovery Charge	_	2.8	4.2	μC	di/dt=100A/μs ④	
ton	Forward Turn-On Time	Intrinsic turn-on time is neglegible (turn-on is dominated by Ls+LD)					

#### Notes:

- Repetitive rating; pulse width limited by max. junction temperature (See Figure 11)
- ③ I<sub>SD</sub>≤10A, di/dt≤120A/μs, V<sub>DD</sub>≤V(BR)DSS, T<sub>J</sub>≤150°C
- ⑤ t=60s, f=60Hz

- ④ Pulse width ≤ 300 µs; duty cycle ≤2%.

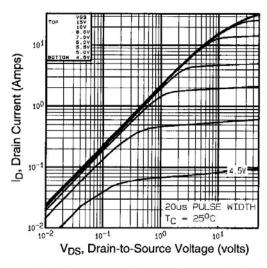


Fig 1. Typical Output Characteristics, T<sub>C</sub>=25°C

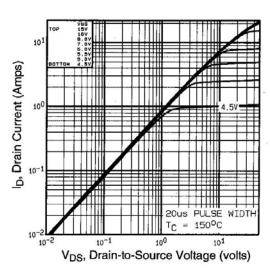


Fig 2. Typical Output Characteristics, T<sub>C</sub>=150°C

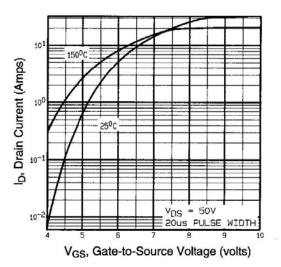


Fig 3. Typical Transfer Characteristics

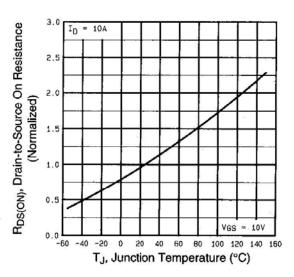
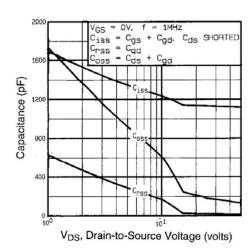


Fig 4. Normalized On-Resistance Vs. Temperature



**Fig 5.** Typical Capacitance Vs. Drain-to-Source Voltage

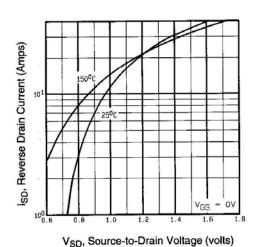


Fig 7. Typical Source-Drain Diode Forward Voltage

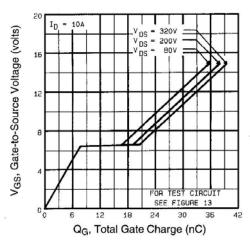


Fig 6. Typical Gate Charge Vs. Gate-to-Source Voltage

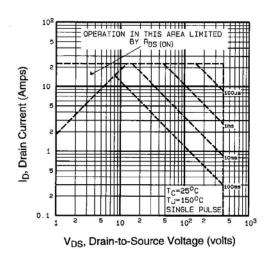


Fig 8. Maximum Safe Operating Area

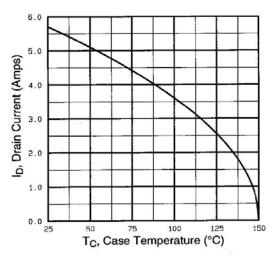


Fig 9. Maximum Drain Current Vs. Case Temperature

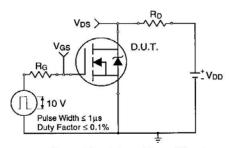


Fig 10a. Switching Time Test Circuit

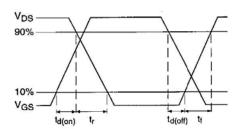


Fig 10b. Switching Time Waveforms

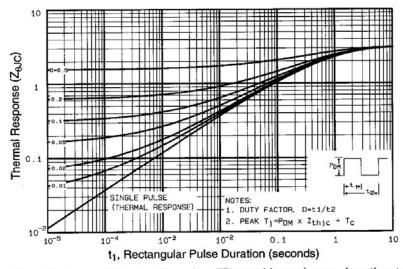


Fig 11. Maximum Effective Transient Thermal Impedance, Junction-to-Case

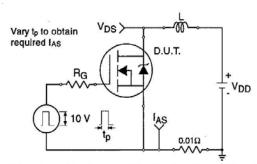


Fig 12a. Unclamped Inductive Test Circuit

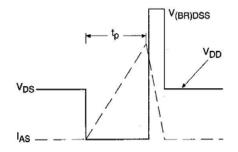


Fig 12b. Unclamped Inductive Waveforms

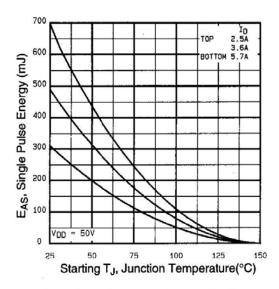


Fig 12c. Maximum Avalanche Energy Vs. Drain Current

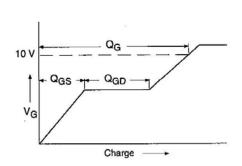


Fig 13a. Basic Gate Charge Waveform

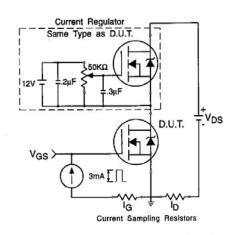
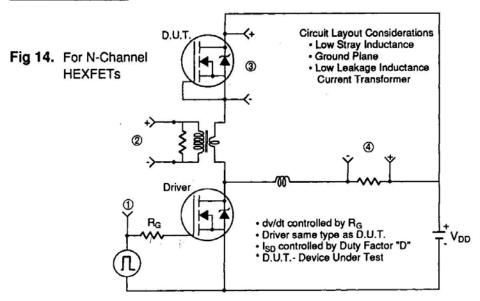
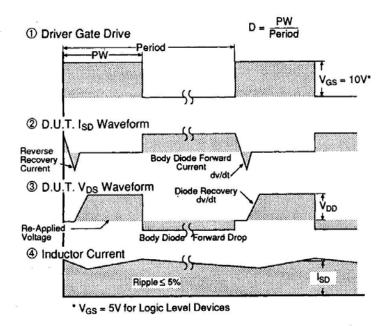


Fig 13b. Gate Charge Test Circuit

# Appendix A

### Peak Diode Recovery dv/dt Test Circuit



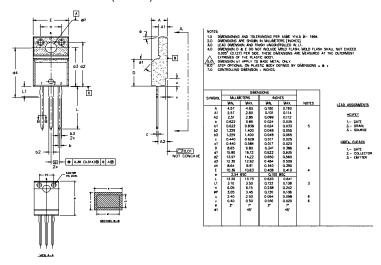


International

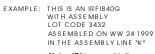
TOR Rectifier

### TO-220 Full-Pak Package Outline

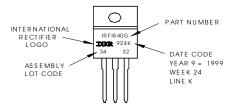
Dimensions are shown in millimeters (inches)



## TO-220 Full-Pak Part Marking Information



Note: "P" in assembly line position indicates "Lead-Free"



Data and specifications subject to change without notice.



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12/03



Vishay

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